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Fischer
(K) 54 084
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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Re: US Patent Application 09/818,036
Filed March 26, 2001
Title Method and apparatus for the nondestructive measurement of the
thickness of thin layers
Applicant Fischer
Attorney Docket (K) 54 084

4 / Prel. Amdt. B
Sub. Spec. N.E.
E. Willis
12-13-01

Box Missing Parts
Commissioner for Patents
Washington, DC 20231

Supplemental Further Preliminary Amendment

Dear Sir or Madam:

In further response to the Notice to File Corrected Application Papers mailed May 31, 2001, please note that a typographical error was unintentionally made in the claims. Inadvertently, two claims were numbered as "21" when in actuality, there should really be one "21" and a "22". A revised set of claims is attached hereto, as well as a version with markings to show changes made.

Respectfully submitted,

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I hereby certify this correspondence is being deposited with the U.S Postal Service as a first class mail in an envelope with adequate postage addresses to Commissioner for Patents, Washington, D.C. 20231 on September 7, 2001.

M. Robert Kestenbaum

09/18/01 09:18:01